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Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/768,443	WARE ET AL.	
Examiner	Art Unit	
Trung Q. Nguyen	2829	

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East Search Keywords: test near circuit\$1 same element\$1 same transmitter same receiver.	2/24/2006	QT	
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